

## THYRISTORS

Silicon thyristors in metal envelopes, primarily intended for three-phase mains operation. The series consists of reverse polarity types (anode to stud) identified by a suffix R: BTW47-800R to 1600R.

## QUICK REFERENCE DATA

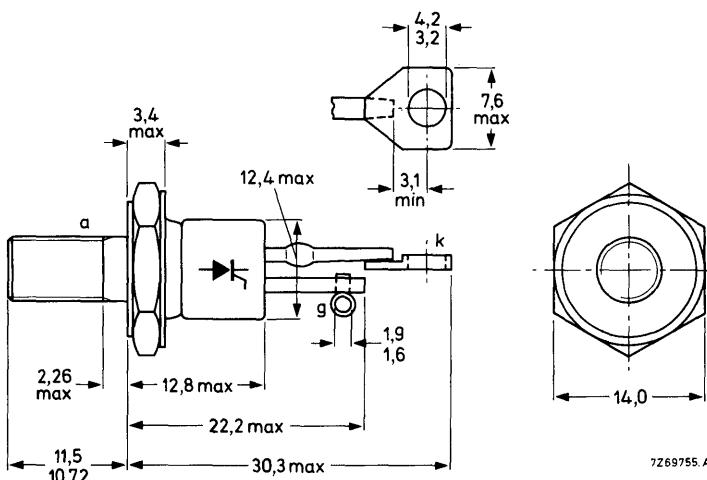
	BTW47-800R	1000R	1200R	1400R	1600R
Repetitive peak voltages $V_{DRM} = V_{RRM}$	max. 800	1000	1200	1400	1600 V
Average on-state current		$I_T(AV)$ max.			16 A
R.M.S. on-state current		$I_T(RMS)$ max.			25 A
Non-repetitive peak on-state current		$I_{TSM}$ max.			300 A
Rate of rise of off-state voltage that will not trigger any device		$dV_D/dt <$			300 V/ $\mu$ s
On request (see ordering note on page 4)		$dV_D/dt <$			1000 V/ $\mu$ s

## MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-48: with metric M6 stud ( $\phi$  6 mm); e.g. BTW47-800R.

Types with  $\frac{1}{4}$  in x 28UNF stud ( $\phi$  6,35 mm) are available on request. These are indicated by the suffix U: BTW47-800RU.



Net mass: 14 g

Diameter of clearance hole: max. 6,5 mm

Accessories supplied on request: 56264A  
(mica washer, insulating ring, soldering tag)

Torque on nut: min. 1,7 Nm (17 kg cm)  
max. 3,5 Nm (35 kg cm)

Supplied with the device:

1 nut, 1 lock washer

Nut dimensions across the flats:

M6: 10 mm

$\frac{1}{4}$  in x 28 UNF: 11,1 mm

**RATINGS**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

**Anode to cathode**

		BTW47-800R	1000R	1200R	1400R	1600R
Non-repetitive peak voltages ( $t \leq 10$ ms)	$V_{DSM}/V_{RSM}$	max. 800	1000	1200	1400	1600 V
Repetitive peak voltages	$V_{DRM}/V_{RRM}$	max. 800	1000	1200	1400	1600 V
Crest working voltages	$V_{DWM}/V_{RWM}$	max. 600	700	800	800	800 V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 77$ °C at $T_{mb} = 85$ °C				$I_T(AV)$	max.	16 A
R.M.S. on-state current				$I_T(AV)$	max.	14 A
Repetitive peak on-state current				$I_{T(RMS)}$	max.	25 A
Non-repetitive peak on-state current; $t = 10$ ms; half sine-wave; $T_j = 125$ °C prior to surge; with reapplied $V_{RWMMAX}$				$I_{TRM}$	max.	150 A
$I^2t$ for fusing ( $t = 10$ ms)				$I_{TSM}$	max.	300 A
Rate of rise of on-state current after triggering with $I_G = 500$ mA to $I_T = 50$ A				$I^2t$	max.	450 A <sup>2</sup> s
Rate of change of commutation current				$dI_T/dt$	max.	200 A/μs
see Fig. 9						
<b>Gate to cathode</b>						
Reverse peak voltage			$V_{RGM}$	max.	10 V	
Average power dissipation (averaged over any 20 ms period)			$P_{G(AV)}$	max.	1 W	
Peak power dissipation			$P_{GM}$	max.	5 W	
<b>Temperatures</b>						
Storage temperature			$T_{stg}$		-55 to +125	°C
Junction temperature			$T_j$	max.	125	°C
<b>THERMAL RESISTANCE</b>						
From junction to mounting base			$R_{th\ j-mb}$	=	1	°C/W
From mounting base to heatsink			$R_{th\ mb-h}$	=	0,2	°C/W
Transient thermal impedance ( $t = 1$ ms)			$Z_{th\ j-mb}$	=	0,06	°C/W

\* To ensure thermal stability:  $R_{th\ j-a} < 1,5$  °C/W (d.c. blocking) or  $< 3$  °C/W (a.c.). For smaller heat-sinks  $T_j$  max should be derated. For a.c. see Fig. 3.

**CHARACTERISTICS****Anode to cathode****On-state voltage** $I_T = 50 \text{ A}; T_j = 25^\circ\text{C}$  $V_T < 3 \text{ V}^*$ 

Rate of rise of off-state voltage that will not trigger any device; exponential method;  $V_D = 2/3 V_{DRMmax}$ ;  $T_j = 125^\circ\text{C}$

 $dV_D/dt < 300 \text{ V}/\mu\text{s}$ **Reverse current** $V_R = V_{RWMmax}; T_j = 125^\circ\text{C}$  $I_R < 5 \text{ mA}$ **Off-state current** $V_D = V_{DWMmax}; T_j = 125^\circ\text{C}$  $I_D < 5 \text{ mA}$ Latching current;  $T_j = 25^\circ\text{C}$  $I_L < 200 \text{ mA}$ Holding current;  $T_j = 25^\circ\text{C}$  $I_H < 200 \text{ mA}$ **Gate to cathode****Voltage that will trigger all devices** $V_D = 6 \text{ V}; T_j = 25^\circ\text{C}$  $V_{GT} > 3,5 \text{ V}$ **Voltage that will not trigger any device** $V_D = V_{DRMmax}; T_j = 125^\circ\text{C}$  $V_{GD} < 200 \text{ mV}$ **Current that will trigger all devices** $V_D = 6 \text{ V}; T_j = 25^\circ\text{C}$  $I_{GT} > 100 \text{ mA}$ **Switching characteristics**

Gate-controlled turn-on time ( $t_{gt} = t_d + t_r$ ) when switched from  $V_D = V_{DWMmax}$  to  $I_T = 10 \text{ A}$ ;  
 $I_{GT} = 150 \text{ mA}$ ;  $dI_G/dt = 1 \text{ A}/\mu\text{s}$ ;  $T_j = 25^\circ\text{C}$

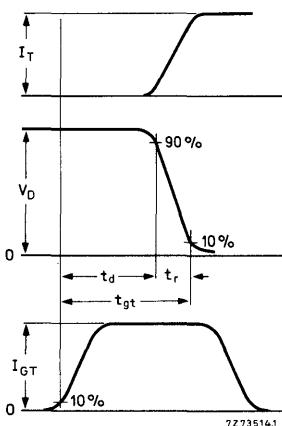
 $t_{gt}$  typ. 2  $\mu\text{s}$   
 $t_r$  typ. 1,2  $\mu\text{s}$ 

Fig. 2 Gate-controlled turn-on time definitions.

\* Measured under pulse conditions to avoid excessive dissipation.

## OPERATING NOTES

1. The terminals should neither be bent nor twisted; they should be soldered into the circuit so that there is no strain on them.

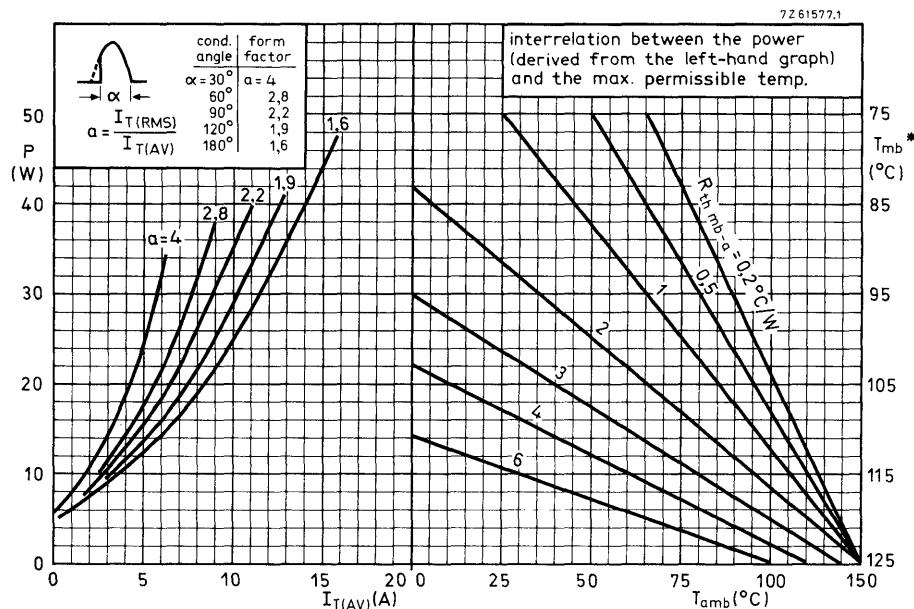
During soldering the heat conduction to the junction should be kept to a minimum.

2. Switching losses in commutation

For applications in which the thyristor is forced to switch from an on-state current  $I_{TRM}$  to a high reverse voltage at a high commutation rate ( $-dI_T/dt$ ), consult Fig. 9 (nomogram) to find the increase in total average power. This increase must be added to the loss from the curves in Fig. 3.

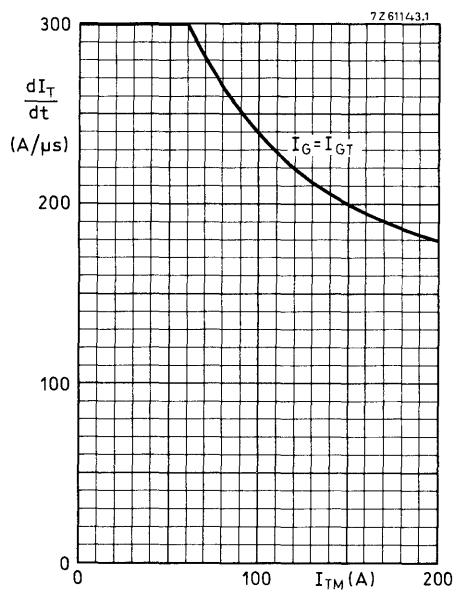
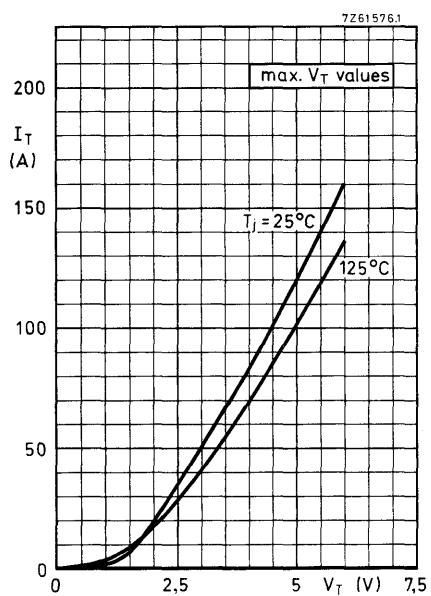
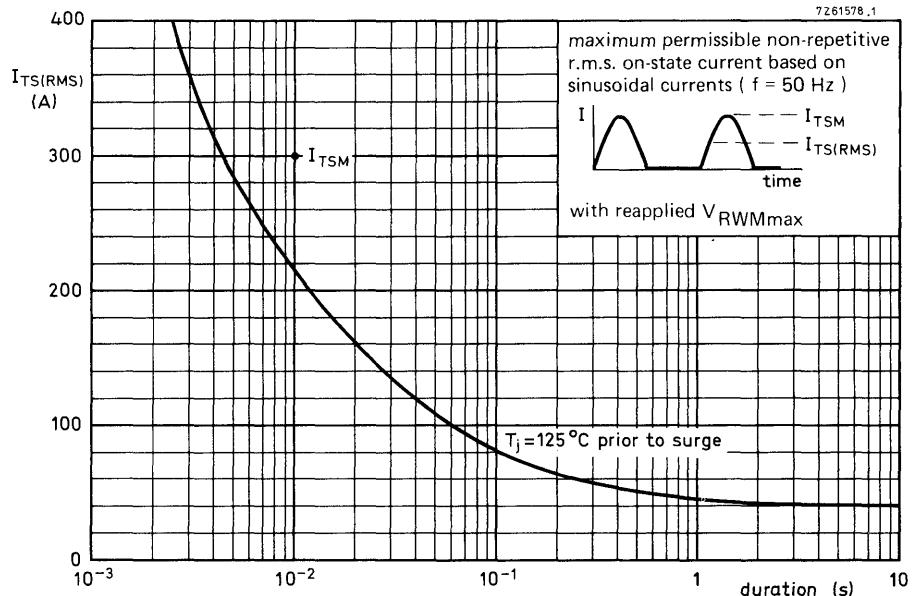
## ORDERING NOTE

Types with  $dV_D/dt$  of 1000 V/ $\mu$ s are available on request. Add suffix C to the type number when ordering; e.g. BTW47-800RC.



\*  $T_{mb}$ -scale is for comparison purposes only and is correct only for  $R_{th\ mb-a} \leq 2^\circ\text{C}/\text{W}$

Fig. 3.



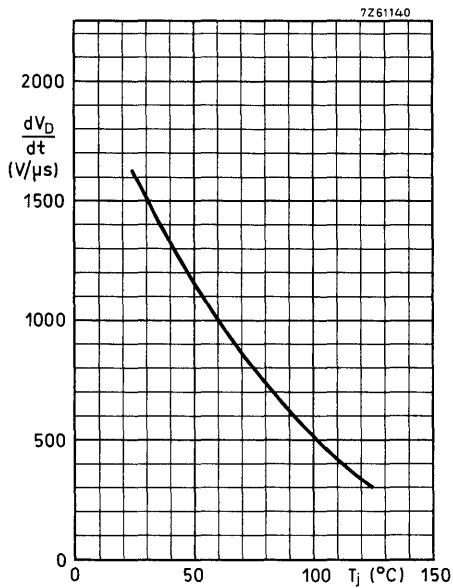


Fig. 7 Maximum rate of rise of off-state voltage that with not trigger any device (exponential method) as a function of  $T_j$ .

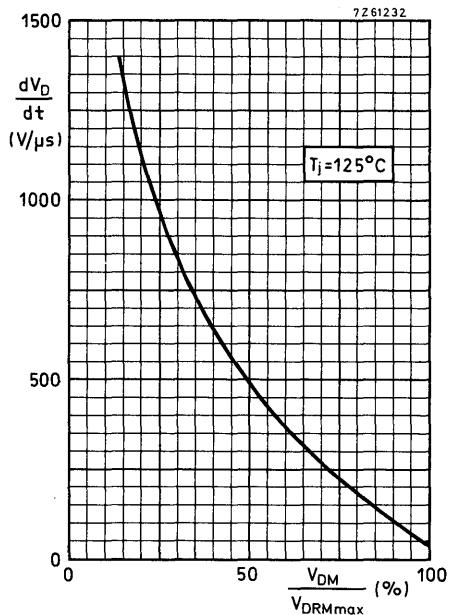


Fig. 8 Maximum rate of rise of off-state voltage that with not trigger any device (exponential method) as a function of applied voltage.

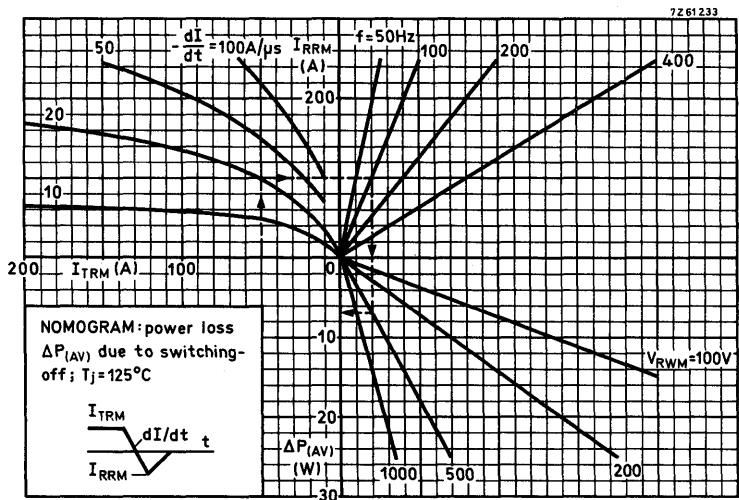


Fig. 9.

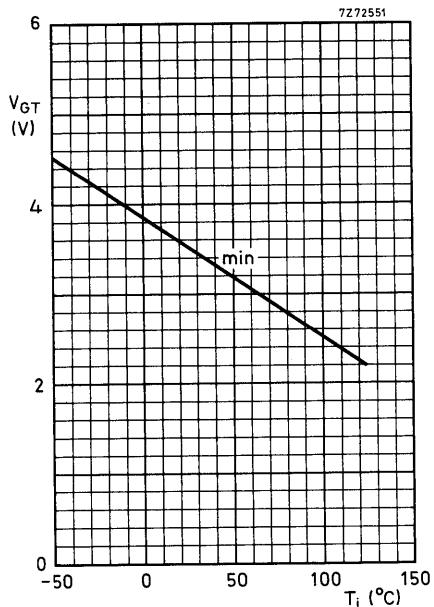


Fig. 10 Minimum gate voltage that will trigger all devices as a function of  $T_j$ .

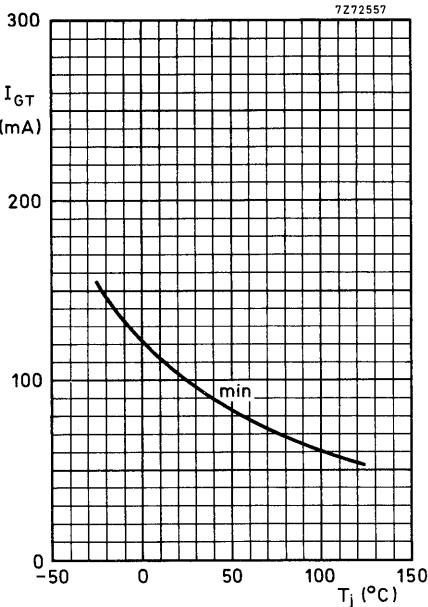


Fig. 11 Minimum gate current that will trigger all devices as a function of  $T_j$ .

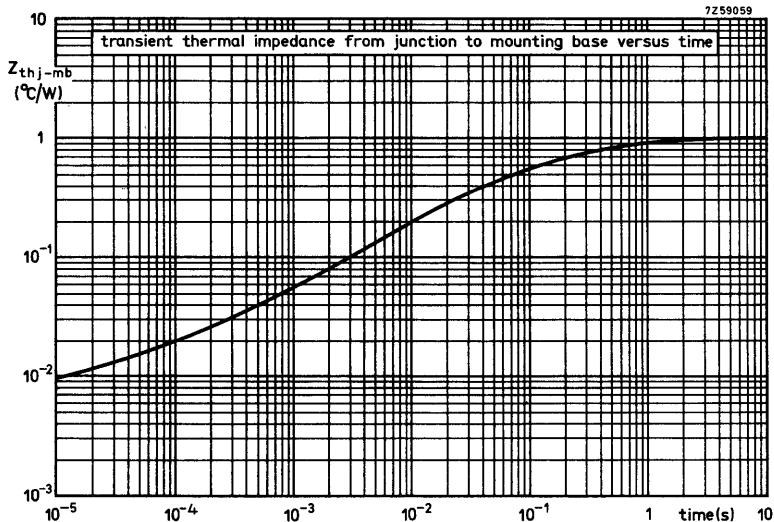


Fig. 12.

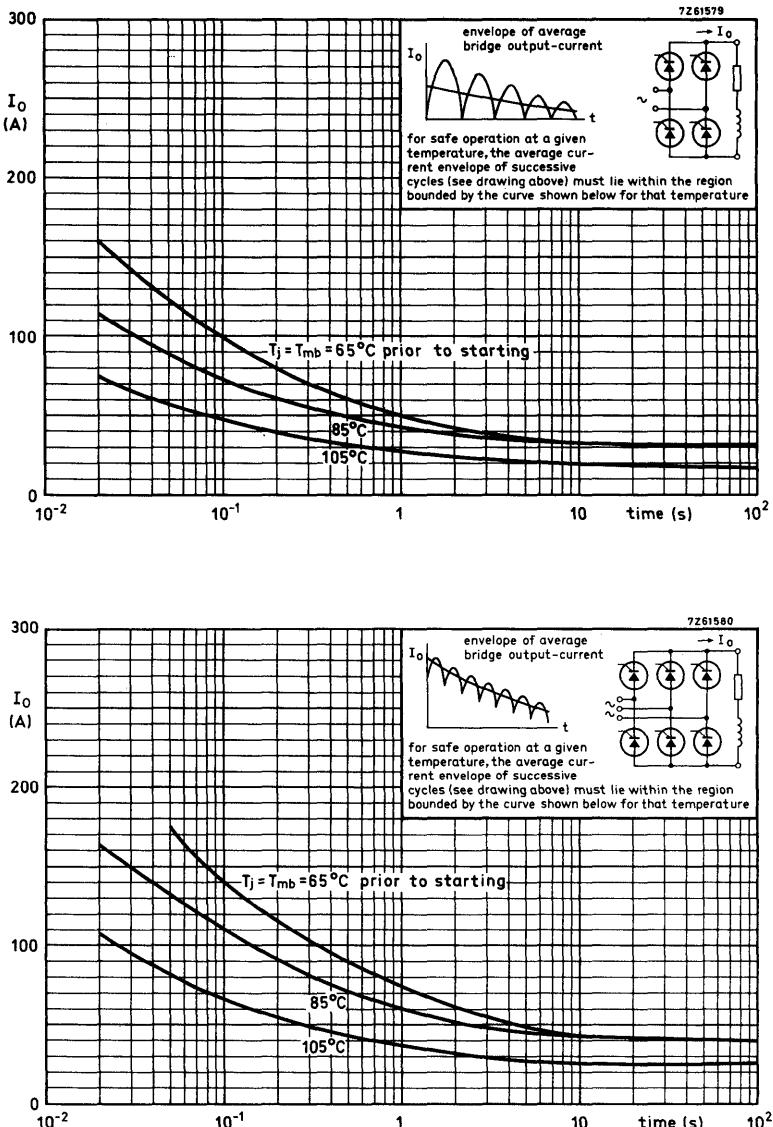


Fig. 13 Limits for starting or inrush currents.